

A Triple-Through Method for Characterizing Test Fixtures

R.P. Meys. "A Triple-Through Method for Characterizing Test Fixtures." 1988 Transactions on Microwave Theory and Techniques 36.6 (Jun. 1988 [T-MTT]): 1043-1046.

Test fixtures for evaluating microwave components such as transistors or MMIC's consist of two "unmeasurable" sections, each having, for example, one coax and one microstrip terminal. A method is proposed for evaluating the S parameters of these sections through three conventional reflection/transmission measurements. It rests on the use of an auxiliary 2-port. No microstrip standard is needed, except for a load that is necessary if the SWR of the auxiliary 2-port is not low enough.

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